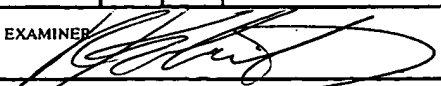

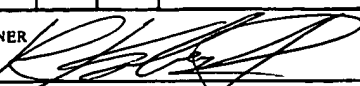


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M171-2523		SERIAL NO. 10/803,294	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Wanda M. Farnworth et al.			
				FILING DATE March 17, 2001		GROUP 2812 2829	
U.S. PATENT DOCUMENTS							
* Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>RA</i>	AA	5580827 5580827	12/03/90	Akorn Inc	437	225	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER <i>[Signature]</i>				DATE CONSIDERED 8-2-04			
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2525		SERIAL NO. Filed Herewith	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Warren M. Farnworth et al.			
				FILING DATE Filed Herewith		GROUP N/A 2829	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
RK	AA	3,412,456	11/68	Ebisawa			
RK	AB	3,469,019	9/69	Reinmann			
RK	AC	4,105,970	8/78	Katz			
RK	AD	4,141,055	2/79	Berry et al.			
RK	AE	4,182,781	1/80	Hooper et al.			
RK	AF	4,189,825	2/80	Robillard et al.			
RK	AG	4,312,117	1/82	Robillard et al.			
RK	AH	4,315,984	2/82	Okazaki et al.			
RK	AI	4,417,206	11/83	Stowers			
RK	AJ	4,499,656	2/85	Fabian et al.			
RK	AK	4,585,991	4/86	Reid et al.			
RK	AL	4,881,118	11/89	Niwayama et al.			
FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
RK	AM	53171	03/91	Japan			
RK	AN	108350	05/91	Japan			
RK	AO	329314	08/89	European (EPO)			
RK	AP	5744636 57443838	09/82	Japan			
RK	AQ	2-5540	01/90	Japan			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
RK	AR	Moto's Nakano "A Probe for Testing Semiconductor Integrated Circuits and a Test Method Using Said Probe." 25 March, 1991					
		Japanese Patent Office Disclosure No. Hei 3-69131, Filing No. Hei 1-205301, Filing Date August 8, 1989					
	AS						
	AT						
EXAMINER 			DATE CONSIDERED 8-2-04				
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2525		SERIAL NO. Filed Herewith	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Warren M. Farnworth et al.		FILING DATE Filed Herewith	
				GROUP N/A		2829	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
RK	AU	4,924,589	5/90	Leedy			
RK	AV	4,929,999	5/90	Hoebrechts et al.			
RK	AW	4,937,653	6/90	Blonder et al.			
RK	AX	4,952,272	8/90	Okino et al.			
RK	AY	4,963,225	10/90	Lehman-Lemar			
RK	AZ	5,420,520	5/95	Anschel et al.			
RK	BA	5,014,161	5/91	Lee et al.			
RK	BB	5,032,541	7/91	Sakamoto et al.			
RK	BC	5,045,780	9/91	Swart			
RK	BD	5,072,116	12/91	Kawade et al.			
RK	BE	5,103,557	4/92	Leedy			
RK	BF	5,137,461	8/92	Bindra et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
RK	BG	2232946	09/90	Japan			
RK	BH	410446	01/92	Japan			
	BI						
	BJ						
	BK						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	BL		/				
	BM						
	BN						
EXAMINER 				DATE CONSIDERED 8-7-04			
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Warren M. Farnworth et al.				
				FILING DATE Filed Herewith	GROUP N/A 2829			
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
RK	BO	5,177,438	1/93	Littlebury et al.				
LK	BP	5,177,439	1/93	Liu et al.				
RK	BQ	5,196,251	3/93	Bakhru et al.				
RK	BR	5,206,585	4/93	Chang et al.				
RK	BS	5,235,140	8/93	Reele et al.				
RK	BT	5,239,260	8/93	Widder et al.				
RK	BU	5,245,135	9/93	Schreiber et al.				
RK	BV	5,262,718	11/93	Svensen et al.				
RK	BW	5,307,561	5/94	Feigenbaum et al.				
RK	BX	5,323,035	6/97	Leedy				
RK	BY	5,326,428	7/94	Farnworth et al.				
RK	BZ	5,334,804	8/94	Love et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	CA							
	CB							
	CC							
	CD							
	CE							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	CF							
	CG							
	CH							
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2525		SERIAL NO. Filed Herewith	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Warren M. Farnworth et al.			
				FILING DATE Filed Herewith		GROUP N/A 2829	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>RK</i>	CI	5,353,195	10/94	Fillion et al.			
<i>AP</i>	CJ	5,367,253	11/94	Wood et al.			
<i>RK</i>	CK	5,402,077	03/95	Agahdel et al.			
<i>RK</i>	CL	5,419,807	05/95	Akram et al.			
<i>RK</i>	CM	5,431,328	07/95	Chang et al.			
<i>RK</i>	CN	5,478,779	12/95	Akram			
<i>RK</i>	CO	5,468,917	11/95	Brodsky et al.			
<i>RK</i>	CP	5,471,151	11/95	DiFrancesco			
<i>RK</i>	CQ	5,477,087	12/95	Kwakita et al.			
<i>RK</i>	CR	5,523,697	06/96	Farnworth et al.			
<i>RK</i>	CS	5,541,525	07/96	Wood et al.			
<i>RK</i>	CT	5,559,444	09/93	Farnworth et al.			
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	CU						
	CV						
	CW						
	CX						
	CY						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	CZ						
	DA						
	DB						
EXAMINER <i>[Signature]</i>			DATE CONSIDERED 8-2-04				
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Warren M. Farnworth et al.			
				FILING DATE Filed Herewith	GROUP N/A 2829		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>RK</i>	DC	5,625,297	04/97	Amaudov et al.			
<i>RK</i>	DD	5,716,218	02/98	Farnworth et al.			
<i>RK</i>	DE	5,790,337	08/98	Schreiber et al.			
<i>RK</i>	DF	5,831,832	11/98	Gillette et al.			
<i>RK</i>	DG	5,849,633	12/98	Akram			
<i>RK</i>	DH	5,869,787	02/99	Akram			
<i>RK</i>	DI	6,002,266	12/99	Briggs et al.			
<i>RK</i>	DJ	6,093,643	07/00	Akram			
<i>RK</i>	DK	4,566,184	01/86	Higgins et al.			
<i>RK</i>	DL	5,838,160	11/17/1998	Beaman et al.			
<i>RK</i>	DM	4,571,540	2/18/1986	Stowers et al.			
<i>RK</i>	DN	4,116,523	09/26/78	Coberly et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	DO						
	DP						
	DQ						
	DR						
	DS						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	DT		/				
	DU						
	DV						
EXAMINER <i>[Signature]</i>				DATE CONSIDERED 8-204			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							